

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/791,601	WON ET AL.	
	Examiner	Art Unit	Page 1 of 1
	Brian E. Miller	2627	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0146661	07-2006	Ke et al.	369/044.14
*	B	US-2005/0195702	09-2005	Hong et al.	369/044.14
*	C	US-2004/0181798	09-2004	Song et al.	720/684
*	D	US-2003/0193854	10-2003	Lee et al.	369/44.16
*	E	US-2002/0172109	11-2002	Fujita, Masayuki	369/44.16
*	F	US-2002/0021651	02-2002	Hong et al.	369/112.23
*	G	US-7,028,318	04-2006	Tajiri, Noboru	720/684
*	H	US-6,163,416	12-2000	Uekusa et al.	359/813
*	I	US-6,034,940	03-2000	Lee, Kwang-Suk	720/685
*	J	US-6,016,292	01-2000	Lee, Kwang-Suk	369/44.15
*	K	US-5,787,067	07-1998	Song, Ki-Seog	720/687
*	L	US-5,566,149	10-1996	Song, Ki S.	369/44.15
*	M	US-5,475,661	12-1995	Tomita et al.	369/44.16

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.